

DT15 Rec'd FCT/PTO 06 JAN 2005

FORM PTO-1449	SERIAL NO. 10/520743 Not yet assigned	CASE NO. 10808/199
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	FILING DATE 8-8-05 Herewith	GROUP ART UNIT Not yet assigned 2823
(use several sheets if necessary)	APPLICANT(S): Rodger Fehlhaber et al.	

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER <small>Number-Kind Code (if known)</small>	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
WC	A1	6,225,201 B1	May 1, 2001	Gardner et al.	—	
WC	A2	6,008,096	December 29, 1999	Gardner et al.	—	
WC	A3	5,397,909	March 14, 1995	Moslehi	—	
WC	A4	5,391, 510	February 21, 1995	Hsu et al.	—	

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER <small>Number-Kind Code (if known)</small>	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES OR NO
WC	A5	WO 02/47146 A2	June 13, 2002	WO	—	
WC	A6	JP 02 060131 A	February 28, 1990	Japan	—	

OTHER ART – NON PATENT LITERATURE DOCUMENTS

EXAMINER INITIAL		(include name of author, title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date page(s), volume-issue number(s), publisher, city and/or country where published.
WC	A7	XP 000648245, S.A. Abbas and I.E. Madgo, <i>Formation of Sub-Micron Patterns with Negligible Tolerance</i> , pgs. 2732-2738, IBM Disclosure Bulletin, Vol. 26, No. 6, November 1983.
WC	A8	Copy of International Search Report from International application number PCT/DE03/02072.
WC	A9	Copy of International Examination Report from International application number PCT/DE03/02072.

EXAMINER 	DATE CONSIDERED 06/16/2006
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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